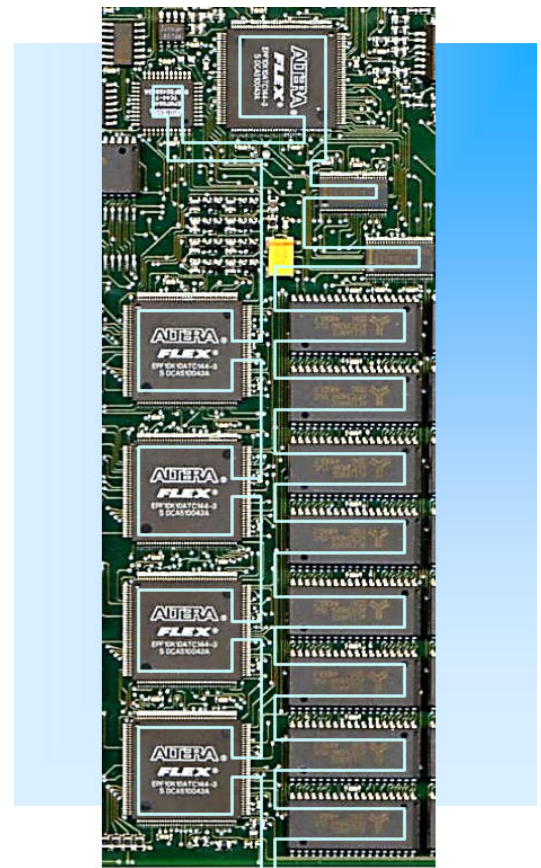


Boundary Scan Test BST-CT3XX

- Real and complete combinational test with BST, MDA/ICT, functional test and AOI
- The BST is fully integrated in the tester operating system "Test OS"
- Only one adapter for all test types, incl. BST
- Compact test program MDA, FT, BST
- Exact logging for each test step ✓ Direct coupling with paperless repair station
- Total product "under one roof"
- CT3XX with dynamic high-speed tests
- No additional hardware for the BST required
- The digital modules DM300 can be used for- Boundary Scan Test hardware interface- Digital tests

Simple coupling to the test system

The test object is simply coupled directly to the digital module DM300. The controlling is completely performed via the tester operating screen. There are no costs for otherwise relatively expensive and specialized test access modules. The DM300 is normally installed in each test system for functional tests. One (1) digital module can simultaneously control parallel 4 BST chains. The data rate is determined here only through the test object. The



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Example for the easy BST controlling

Vec	Stimuli Values		Acquisition - Expected Values		Acquisition - Captured Values	
	LED[8..1]	UOUT1	LED[8..1]	LED0	LED[8..1]	LED0
2	'00000001'	1	'00000001'	'1'	'00000001'	'1'
3	'00000010'	1	'00000010'	'0'	'00000010'	'0'
4	'00000100'	1	'00000100'	'0'	'00000100'	'0'
5	'00001000'	0	'00001000'	'0'	'00001000'	'0'
6	'00010000'	0	'00010000'	'0'	'00010000'	'0'
7	'00100000'	0	'00100000'	'0'	'00100000'	'0'

Signal	Value	Time
UOUT1	1	33.33 µs
LED0	0	66.67 µs
LED1	1	100.00 µs
LED2	0	133.33 µs

Data Logging

- Read_ADC - Device-Id-Code check of 'IC1': captured '0000 0010000010100001 00001101110 1'
- Read_ADC - Device-Id-Code check of 'IC2': captured '0001 0111000000110010 00001101110 1'